

Spurious Electron and S2-Only Backgrounds at DarkSide-50

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on behalf of the DarkSide-50 Collaboration

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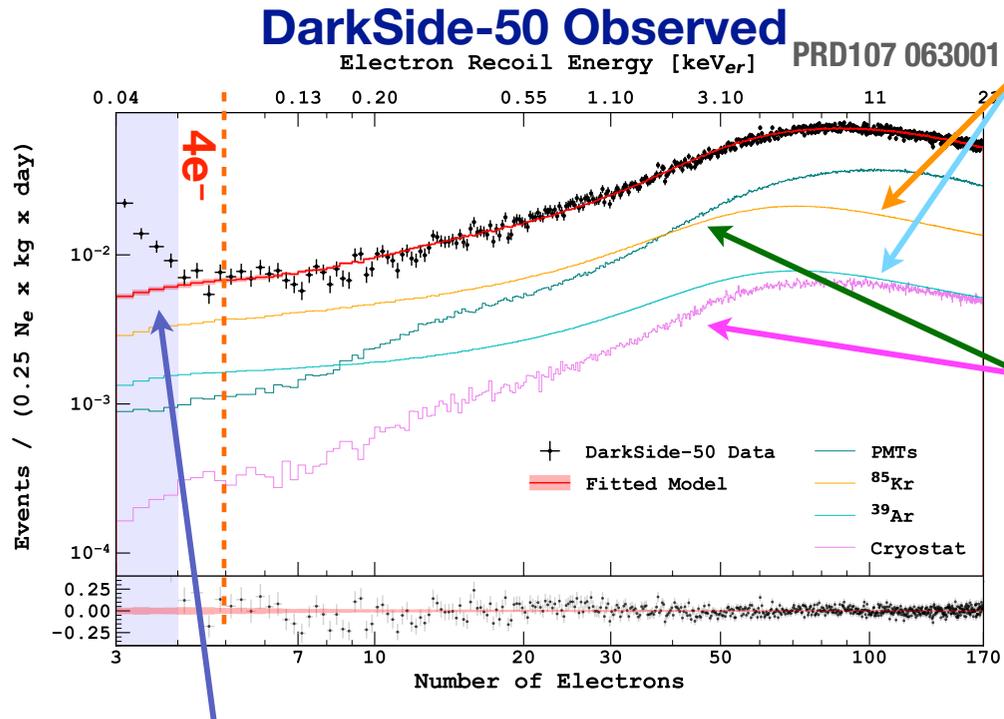


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What Limit The Sensitivity?

in the DarkSide-50 S2-only analysis



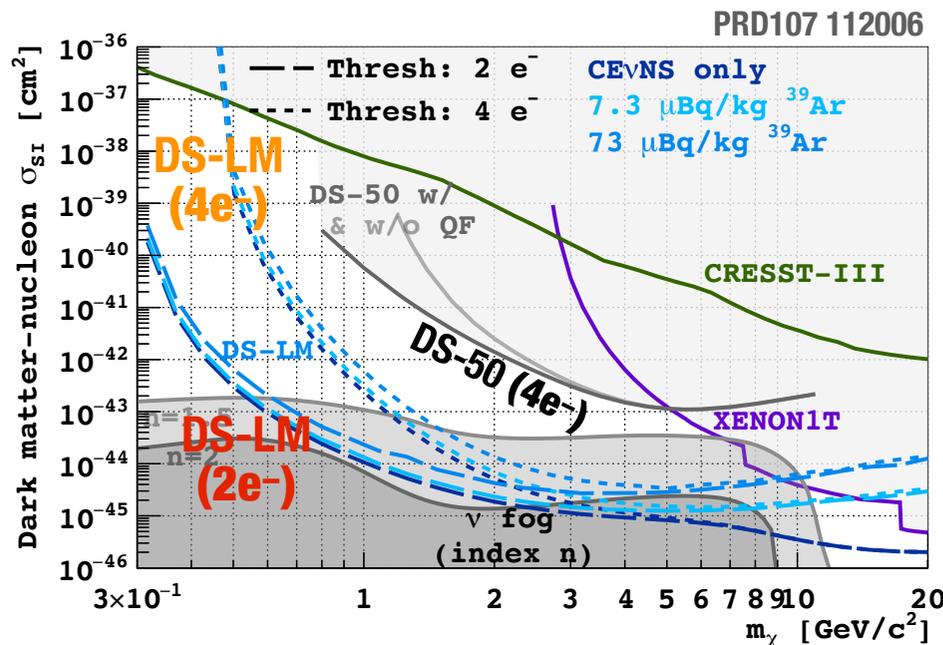
- ① Spurious Electrons (SEs) below 4e⁻
→ Focused on this talk

- ② Diffused β-isotopes inside the bulk LAr (⁸⁵Kr and ³⁹Ar)
→ Underground argon & Isotope separation (Federico's talk)
- ③ γs from photo-detectors and Cryostat
→ a) Radio-purification of instruments (such as replacing PMT with SiPM), (Giacomo's talk)
b) Isolating the fiducial volume
- ④ Limited exposure (1.2 ton-days)
→ Bigger detector
- ⑤ Limited understanding of LAr response
→ Low-energy calibration experiment

SE Determine the S2-Only Threshold

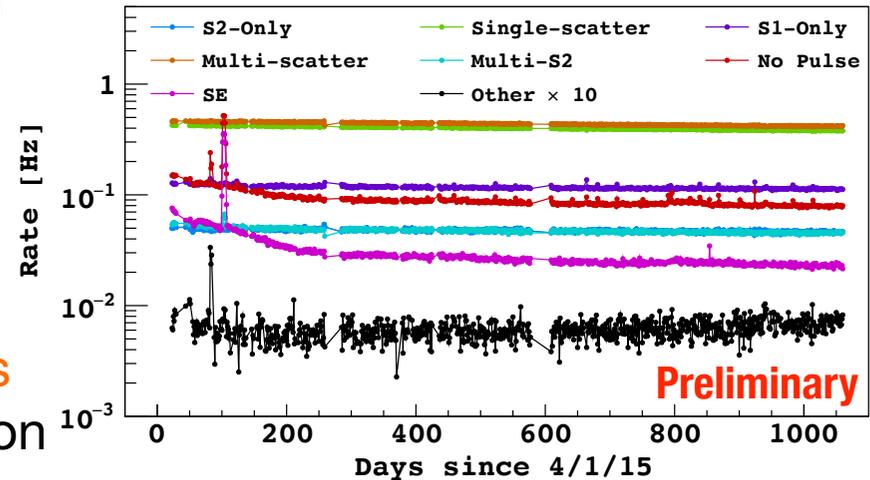
- Energy threshold of the DarkSide-50 S2-only analysis was set at $4e^-$
 - Clear divergence in "Sideband" samples from the background model in $<4e^-$
 - Such as events temporally closed to the previous one, and events during the system maintaining period
 - Resulted in the limited sensitivity to sub-GeV WIMPs

- In a future S2-only-optimized detector ("DarkSide-LM"), projected sensitivity to $m_{\text{wimp}} < 1 \text{ GeV}/c^2$ improves **orders of magnitude** by lowering the threshold from $4e^-$ to $2e^-$.
- The events from unclear source below $4e^-$ is called **spurious electrons (SEs)**
 - must be understood and mitigated



SEs Analysis in DS-50

- DS-50 was operated with underground argon continuously over almost 3 years
- We found that..
 - the observed "normal" event rates were **stable** over the whole data-taking period
 - the observed rate in $<4e^-$ was **$O(10^3-4)$ times higher** than the background model prediction



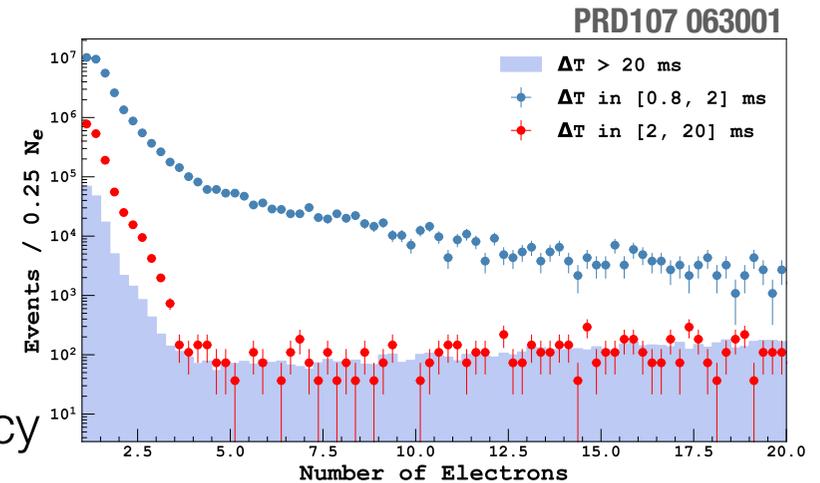
Analysis strategy

- Define **$[0, 4] e^-$ events as a SE sample** and find out its property
 - Particularly focus on its correlations to the preceding events' topology
 - Divide the sample into $1e^-$ bins and investigate how multi-electrons event looks like
 - Discuss about the correlation to the cryogenic system condition
- Discuss possible origins of the SE events along with phenomenological literatures

Properties of The SE Events

Coincidence between SE and Its "Parent"

- Several indications that SEs have its "parent", i.e. a preceding event correlated to each SE event
- Time difference from the previous triggered event (ΔT) is the most sensitive parameter
 - The DS-50 physics analysis simply requires $\Delta T > 20$ ms, corresponding to 97% signal efficiency



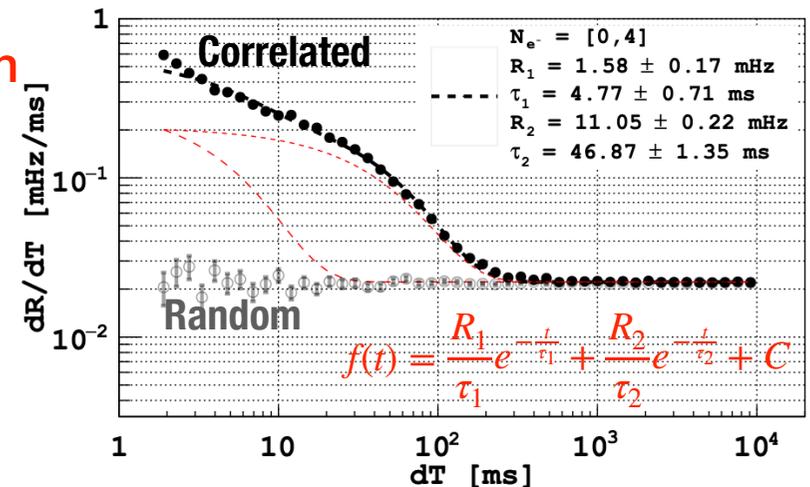
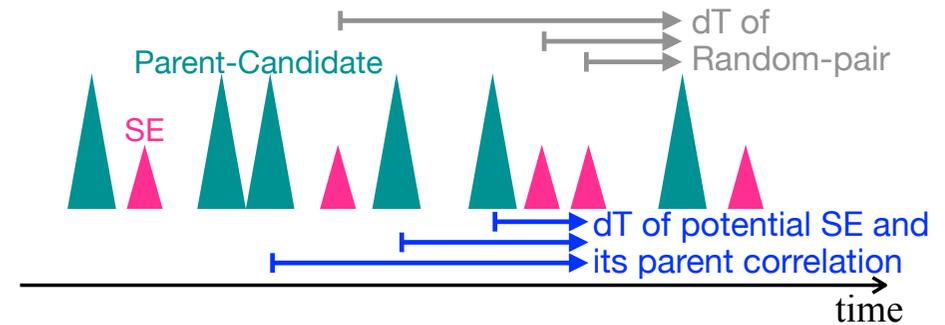
- **The SE analysis on DS-50, discussed here, always relies on the parameter ΔT**

Input behind the analysis (only to those who may be interested..)

- Electroluminescence gain (g_2) is 23 PE/ e^- at the center of the TPC, decreasing by $\sim 30\%$ at the edge of the fiducial volume for S2-only and SE analysis
- Trigger efficiency \otimes pulse-finder efficiency reaches 100% at around $1.3e^-$
- An "event" in DS-50 cannot be defined within ~ 2 ms after the previous trigger due to the DAQ system

Temporal Correlation Analysis

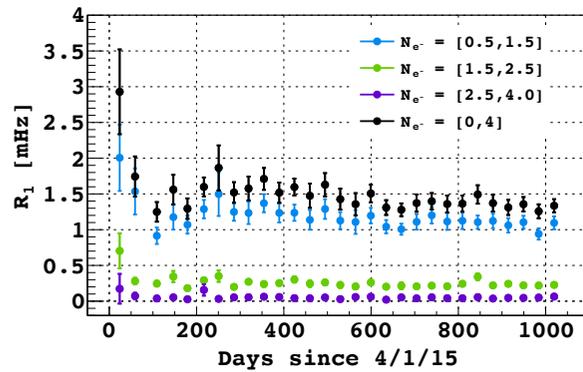
- Define "parent candidate" samples as $S1 > 1000$ PE (~ 150 keV_{ee}) events
- **Correlated dT sample:**
For each SE event, time differences (dT) from all preceding parent-candidate
- **Random dT sample:**
For each parent-candidate, dT from all preceding SE
 - Corresponding only to the accidental pairing
- ▶ **Clear population over the accidental estimation at $dT < 500$ ms**
- ▶ Explained by **two exponentials** with the time-scales of **5 ms** and **50 ms**
 - This may indicate that the origin goes through Poisson process



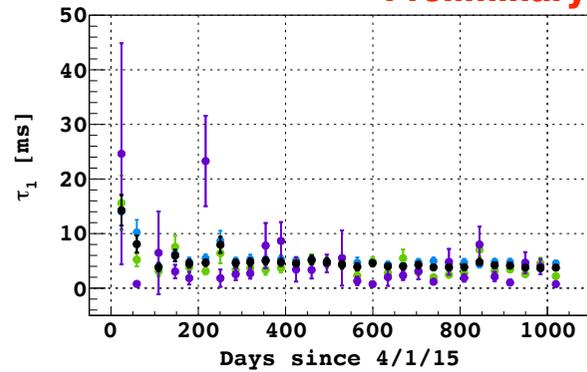
Temporal Evolution

- The same analysis is repeated for each month in each Ne bin

Faster component

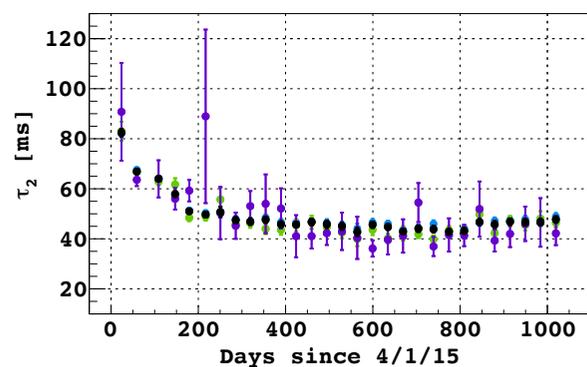
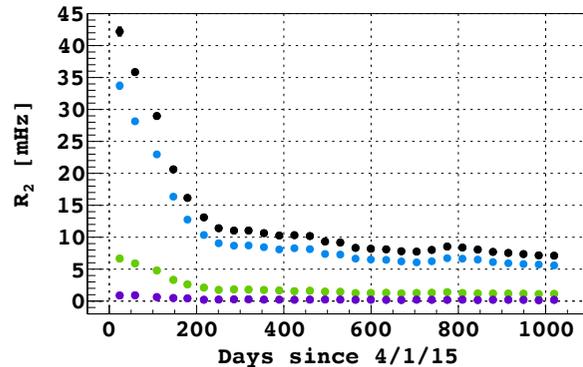


Preliminary



- ▶ The faster-correlated component seems to be stable in both rate and tau
- ▶ The slower-correlated one decreases rapidly within the first 200 days and moderately in the rest

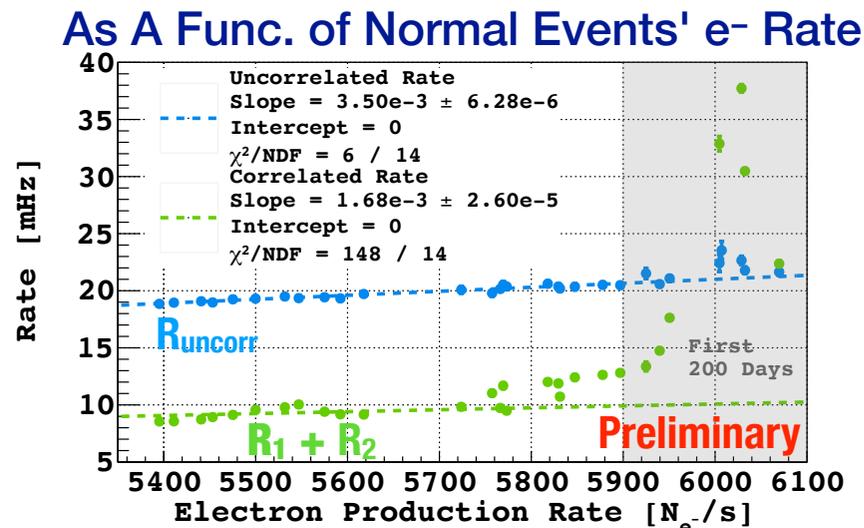
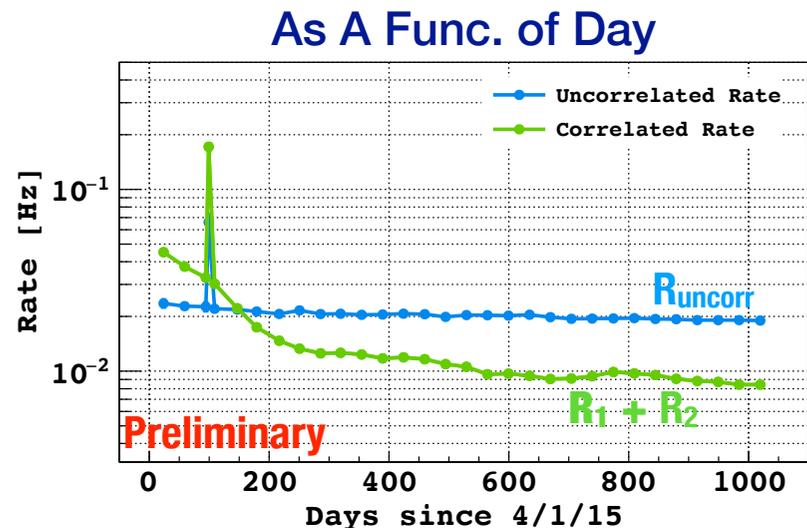
Slower component



- ▶ Consistent behavior in all N_e bins

Temporally Uncorrected Events

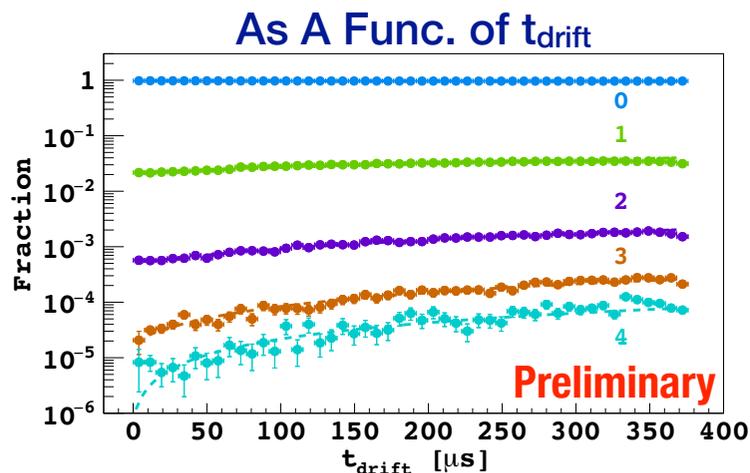
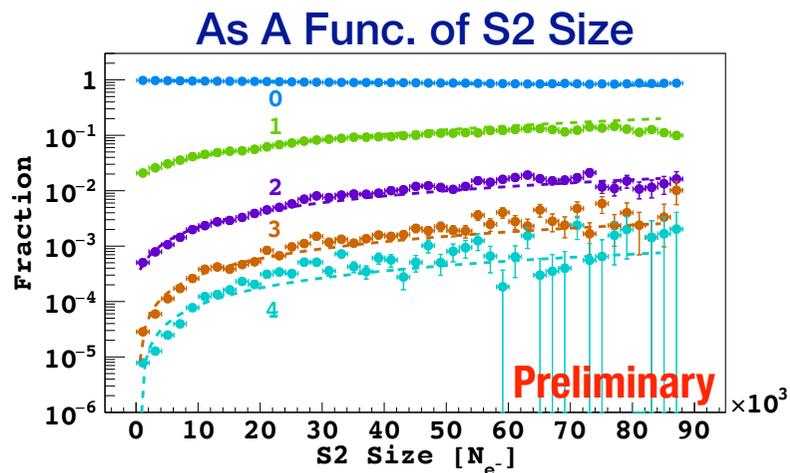
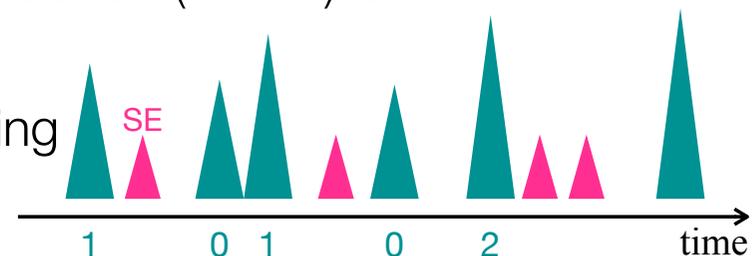
o Definition : Total SE rate = $R_1 + R_2 + R_{\text{Uncorr}}$, where R_1 and R_2 from the dT fit



- ▶ Temporally-correlated component decreases over the period while the uncorrelated one is rather constant
- ▶ Both correlated and uncorrelated rates are roughly proportional to the total e- production rate inside the TPC

SE Following Probability

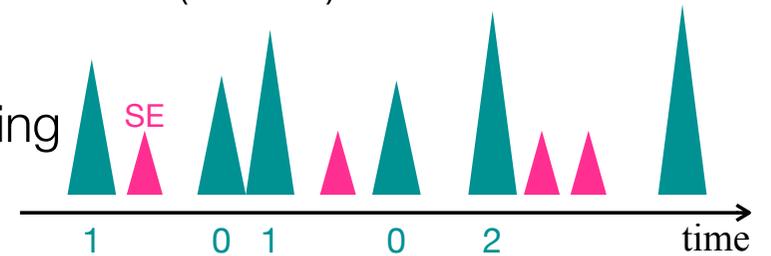
- Pair each SE with the most recent parent candidate to make the parent sample
 - Such pairing makes sense as the time-scale of the correlation (50 ms) is much shorter than the average event rate (~ 1.5 Hz)
- For each parent-candidate, count the number of following SE before the occurrence of next parent-candidate



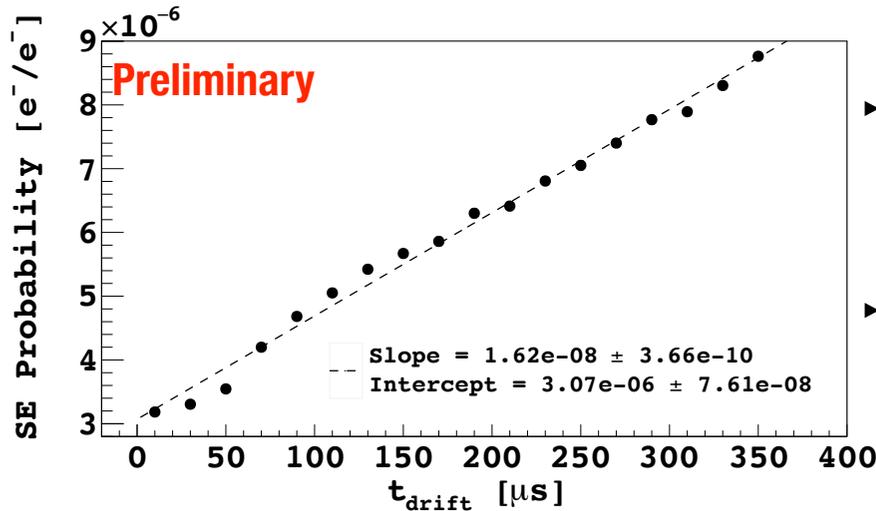
The number of following SEs increases linearly as functions of both S2 and t_{drift} of the parent-candidate

SE Following Probability

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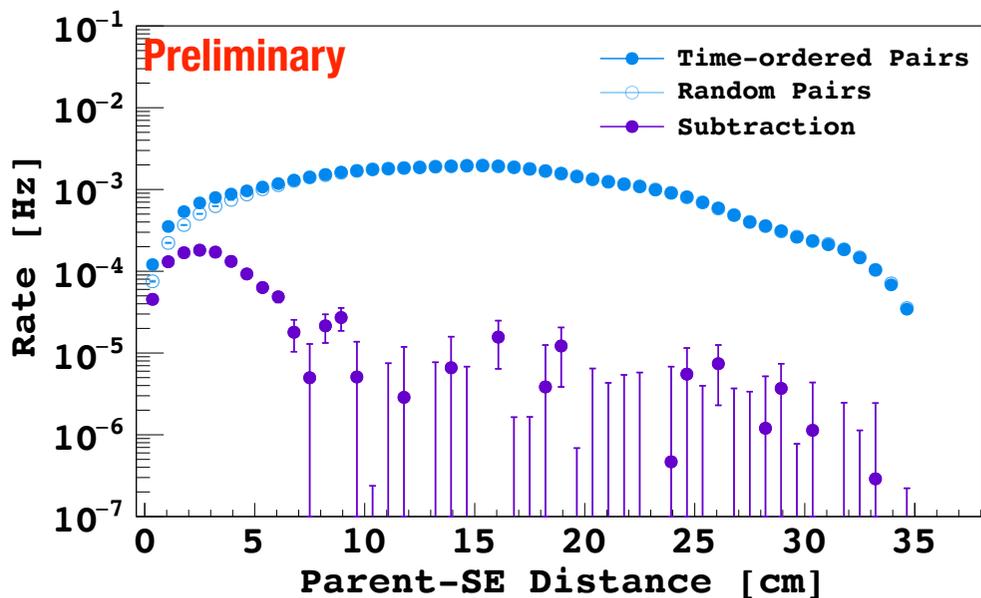
Total charge of all SEs following parent candidates normalized by that of the parent candidates →



- ▶ Temporally-correlated SEs show linear relationship to t_{drift} of parent-candidate
- ▶ Nonzero intercept corresponds to temporally-uncorrelated SEs

Spacial Correlation

- Spacial correlation (in horizontal plane) between SEs and parent-candidate is investigated as with the same way
 - Scanned over events within a 10-sec window



Note:
Uncertainty from the reconstruction algorithm for a few e^- signal is not included yet

Temporally-correlated pairs predominantly reconstructed within 5 cm

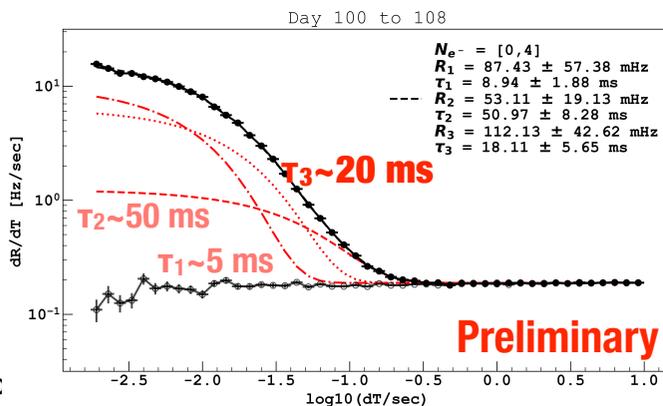
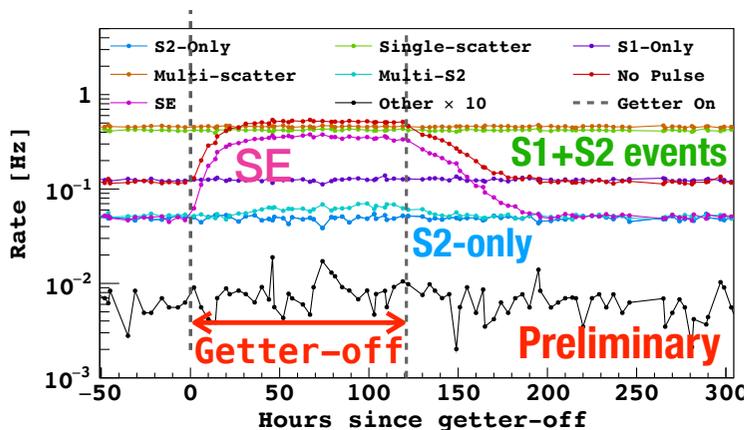
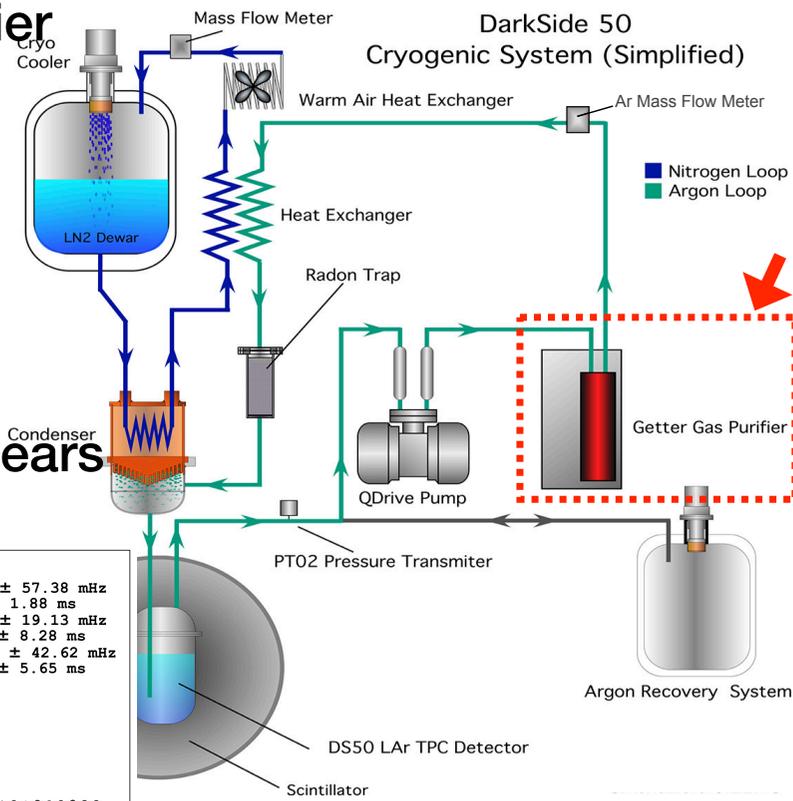
Correlation with The System Condition

-- A few indication the cryogenic system impacts on the SE rate

- Sharp change of the SE rate when the gas purifier getter is bypassed

- x10 increase (plateau) 1-day after bypassing, getting back 3-day after reinstalling
- No change on the "normal" event rate
- No change on the electron lifetime

- An intermediate temporally-correlated term appears



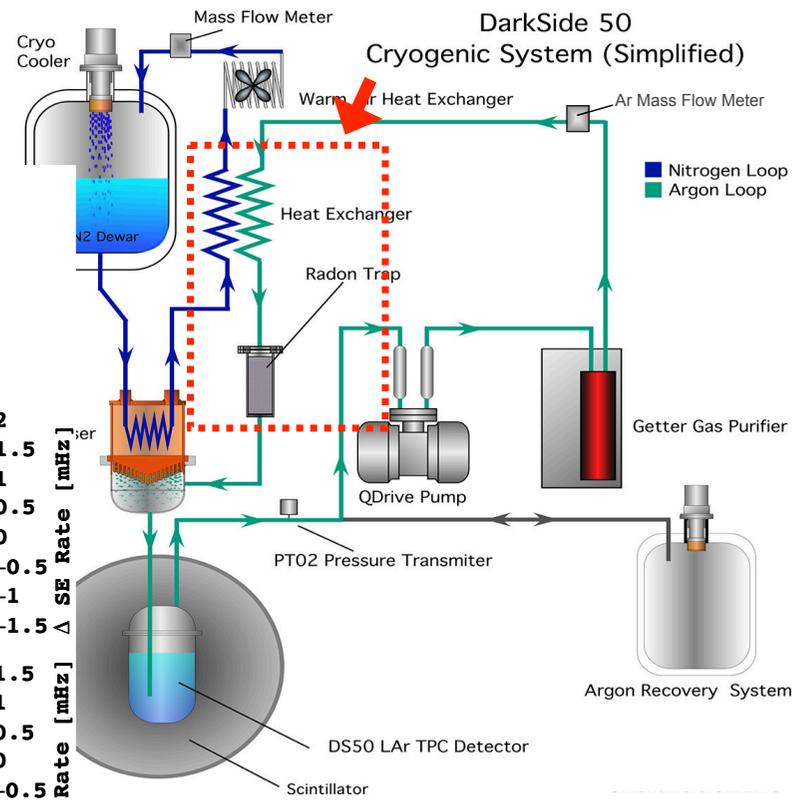
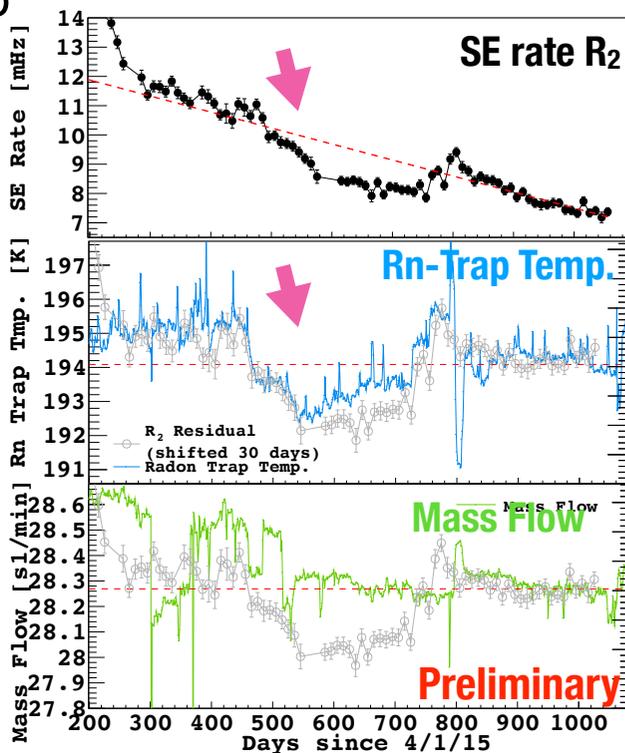
* Getter : Monotrr PS4-MT50-R-2

Correlation with The System Condition

-- A few indication the cryogenic system impacts on the SE rate

o **Delayed coincidence between the correlated rate and Rn-Trap temperature**

- A ~1 year-duration dip in the temporally-correlated rate (R_2) on its gently decreasing trend
- Similar dip in the Rn-trap temperature, with a time-delay of 30-days
- No such structure in other monitoring parameters



* Radon trap is a charcoal filter

Summary of The SE Property 15

	How to analysis	Observation	
		Temporally-Correlated	Random
Components	Look at dR/dT - dT = time difference from paired parent-candidate - dR = observed rate	<ul style="list-style-type: none"> - Two exponentially-temporally-correlated terms ($\tau_1 \sim 5$ ms and $\tau_2 \sim 50$ ms) - Random (temporally-uncorrelated) term 	
Absolute Rate	dR/dT	<ul style="list-style-type: none"> - 60% \rightarrow 30% of the total SE - The longer one gets decreased over years 	<ul style="list-style-type: none"> - 40% \rightarrow 70% of the total SE - Rather constant over years
Corr. with the total activity in TPC	SE rate vs. S2 rate	- Roughly linear	- Roughly linear
Corr. with the parent's size	Look at the most recent parent-candidate	- Linear	N/A
Corr. with the parent's position		- Looks exist	N/A
Corr. with the system	getter-off period	<ul style="list-style-type: none"> - Clearly exist - Additional term ($\tau_3 \sim 20$ ms) appears 	- Clearly exist
	Look together with slow-monitoring parameters	- A hint with the correlation to the Rn-trap temperature	- Not observed

Summary of The SE Property 16

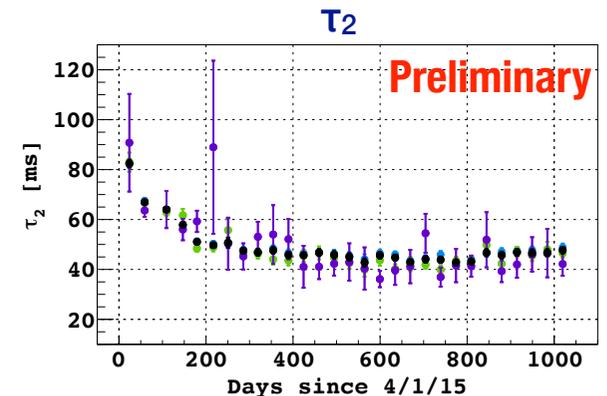
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	Look together with slow-monitoring parameters	- A hint with the correlation to the Rn-trap temperature	- Not observed

- ▶ Drifting- e^- is rarely captured by something during its path and released afterwards?
- ▶ Small electron signal is produced inside the TPC by some mechanism related to the TPC activity?

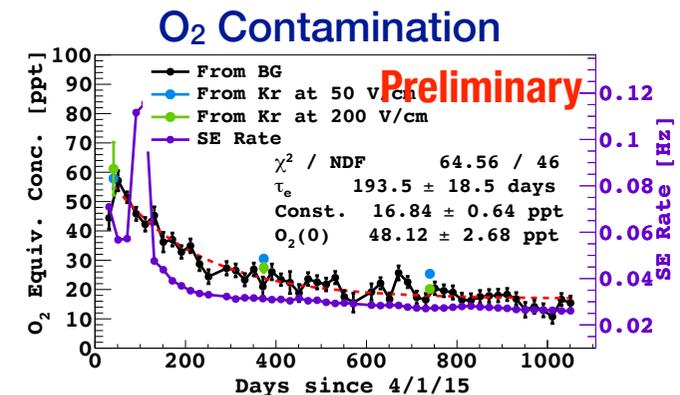
Discussion on Source(s) of The SEs

Source of SE : e⁻ release from impurity ¹⁸

- A possible source of the correlated SE:
 - "e⁻ captured by an impurity and re-emitted with delay"
 - There should be at least two kinds of impurity corresponding to τ_1 and τ_2 ;
 - Observed change of τ_2 over time may imply that it consists of several impurities having similar lifetime (e.g. 40 and 80 ms)



- O₂ is unlikely the source, since drifting-electron lifetime measurement shows different temporal evolution
- N₂ of \geq ppm level is also unlikely, as the S1 triplet lifetime is found to be stable over the period



- Trace moisture may be, as OH⁻ is known to have long resonance time to release e⁻ (J.Am.Chem.Soc.106, 3402 & J.Chem.Phys.39,3209)
- TPB dissolved in LAr may be, as such benzenoid molecules have long-lived anionic states

Source of SE : Biexcitonic ionization ¹⁹

- Another possible source of the correlated SE:
 - "e⁻ emitted from long-lived metastable state excited by δ -ray"
 - Argon is known to have two metastable states having lifetime of ~ 1 min, and TPB may have such long-lived states as well (PRA17,1117 & IEEE Trans.Dielectr.Electr.Instr.11,649)
 - These states (M^{*}) may produce electron via Penning or Associative ionization:



- There should be parent-SE correlation in time and space, and the SE rate should be proportional to the parent energy, while the rate should be independent from parent's t_{drift}
 - This cannot be an only source of the SE
- If the relevant lifetime of metastable states is too long, we may find it as "uncorrelated" SE

Source of SE : Other possibilities

○ Delayed e⁻ extraction

(J.Phys.C19, 4329 & Phys.Rev.158, 305)

- Extracted e⁻ backscatter in GAr may reflect back into LAr; it may be trapped at the surface for a while and re-enter the gas phase
- Both extrapolation from measurement in literature and theoretical calculation predict the timescale of μsec for these process under the DS-50's field (2.8 kV/cm); Therefore, it is unlikely the source in our case

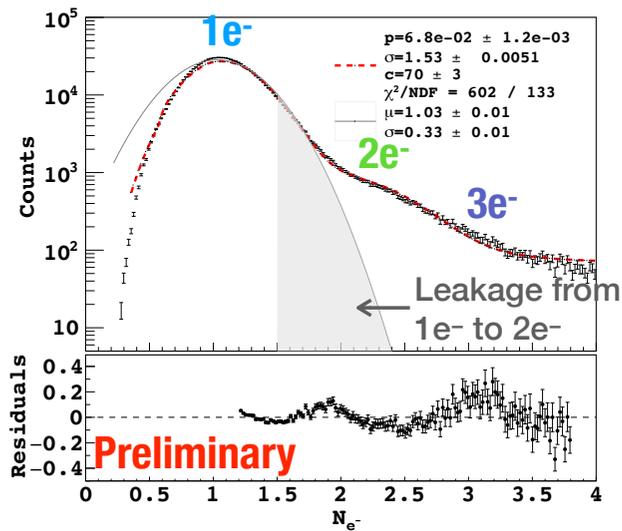
○ Radical impurity cluster interactions

(PRD105, 063002 & PRA38, 364)

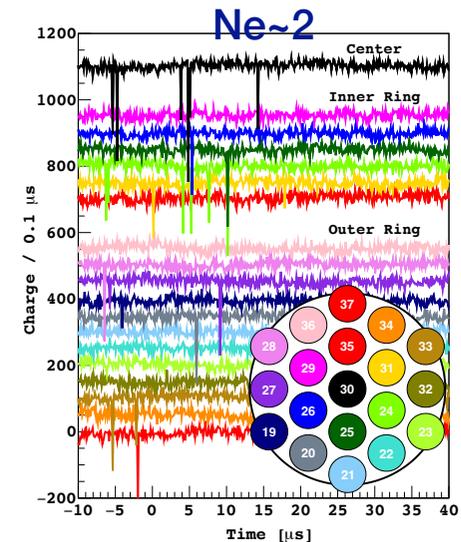
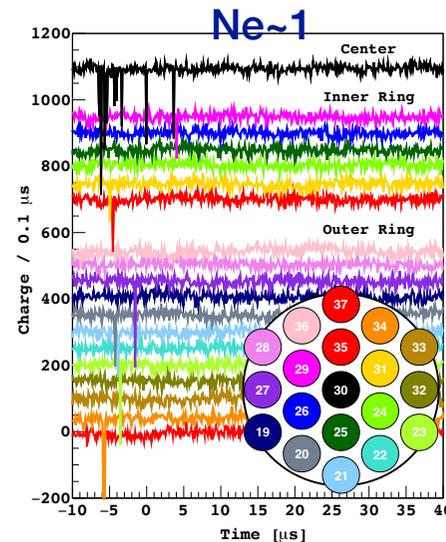
- Radical impurities may exist in LAr and be induced defects from ionization events, which may then cluster together and release a burst of electrons
- Such electrons are expected to follow a parent by a power-law (diffusion driven), but none of our observation is consistent to power-law

Source of Multi-Electrons Signal ²¹

- We clearly observed $2e^-$ and $3e^-$ events
- Accidental coincidence of independent $1e^-$ events **cannot** be their origin
 - Temporally-correlated SE has the rate of $O(10 \text{ mHz})$
 - Two S2 pulses separated in $>2 \mu\text{s}$ are reconstructed as individual pulses
 - Probability for two pulses falling within $2 \mu\text{s}$ is obviously much smaller than the observed multi-electron signal rate



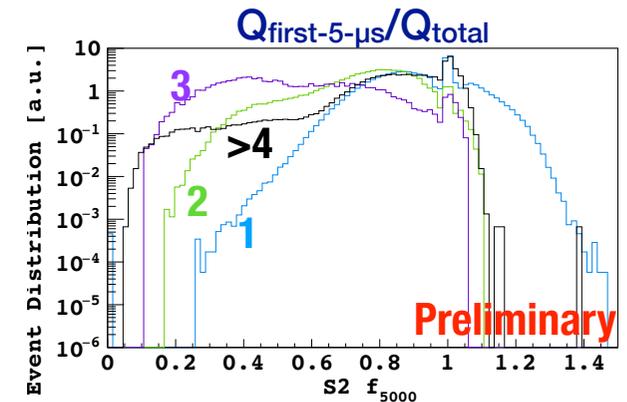
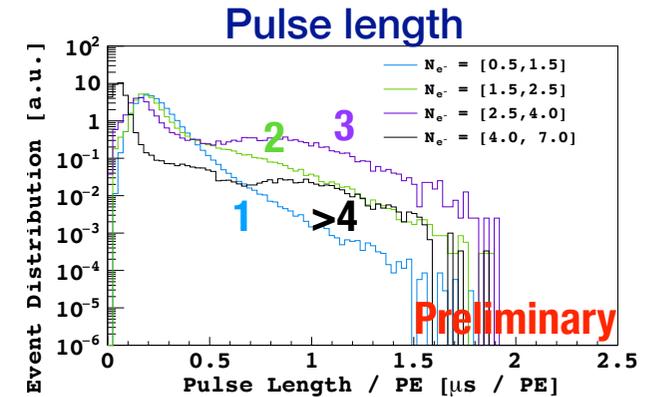
Typical Event Waveforms



Source of Multi-Electrons Signal 22

- Several sources could contribute in a comparable level
 - Their pulse-shape parameters are not perfectly consistent to the $1e^-$ nor $>4e^-$ ones
 - The fraction of $>1e^-$ to $1e^-$ may slightly increase as time passes

- Yet to be concluded about the source of such signals
 - Main challenge from significant leakage into $2-4e^-$ from $1e^-$ event
 - A detector with better resolution and enhanced SE rate may be needed



Summary

- Spurious electrons (SEs) prevents us from digging into the low-mass region
- Dedicated analysis with DS-50 physics run data shows that
 - Significant fraction of SEs follows its "**parent**" **within <100 ms**,
 - **Higher energy parent** produces **more daughter SEs**,
 - There is also SEs that seem to be **randomly** produced, and
 - Some of **getter-gas-purifiers** somehow affect SE rate
- Promising hypotheses about the sources are
 - 1) **electronegative impurities** (but the species are unknown) capturing and reemitting drift electrons, and
 - 2) Delayed emission of electron from **biexcitonic molecules**
- There is also **2-4e⁻ SE events**, but its origin may differ from **1e⁻ SE**

A dedicated paper will be posted on arXiv soon!

MEMBERS OF MY GROUP



▶ **Azam Zabihi**

- ▶ **PostDoc** working on Medical applications



▶ **Andre Cortez**

- ▶ **PostDoc** expert on gas and liquid noble detectors



▶ **Iftikhar Ahmad**

- ▶ 4th year **PhD student** working on SiPM development



▶ **Paul Zakhary**

- ▶ 4th year **PhD student** working on low energy calibration



▶ **Clea Sunny**

- ▶ 2nd year **PhD student** working on low energy calibration

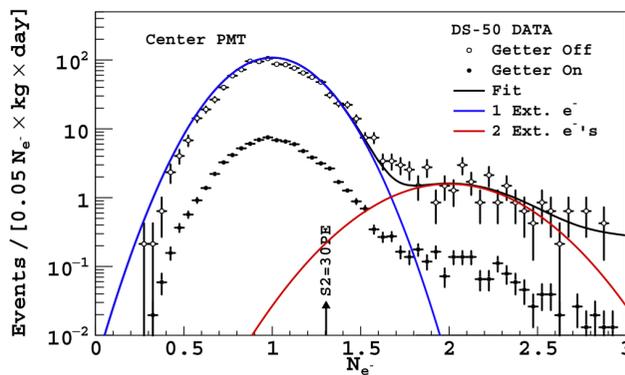
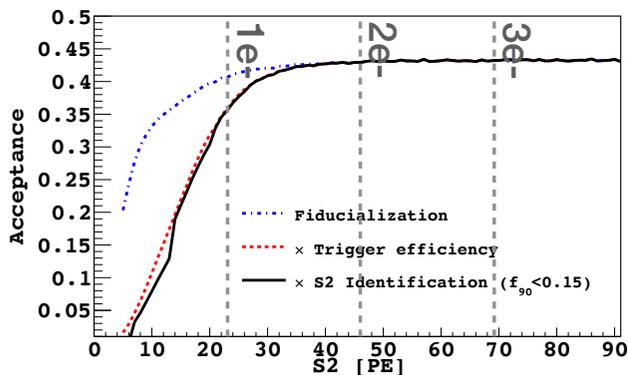
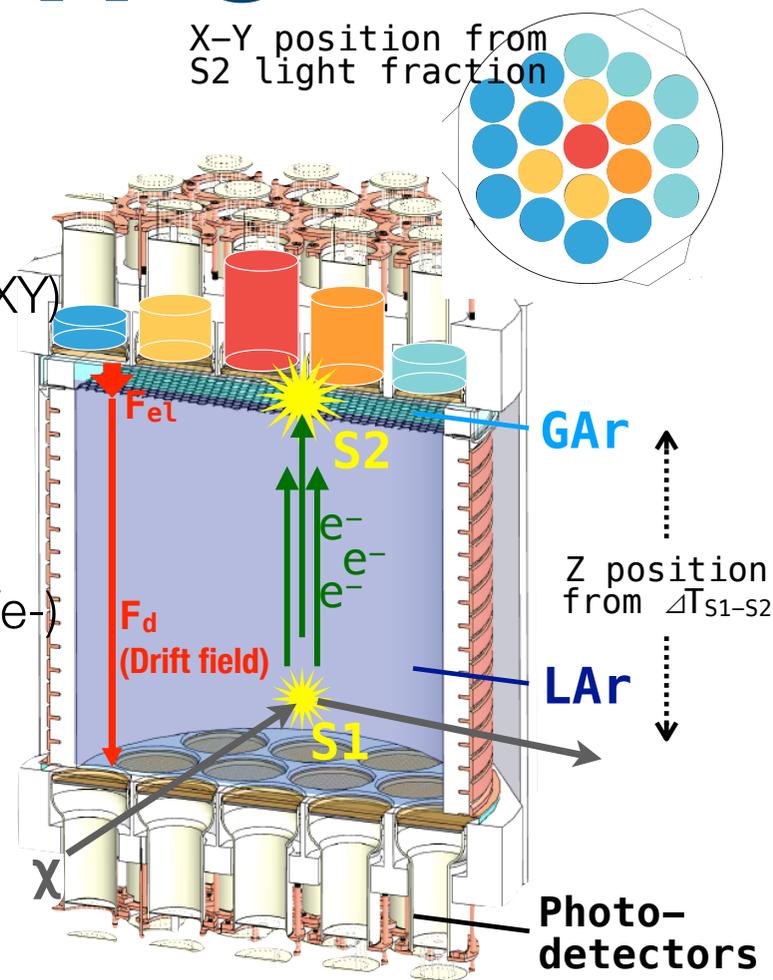
One postdoc position is open!!

If you are interested, contact me at masayuki@camk.edu.pl

Backup

Dual-Phase Argon TPC

- Two time-separated light signals; primary **scintillation (S1)** and secondary **electroluminescence** from ionization e^- (**S2**)
- **3D position reconstruction** by ΔT_{S1-S2} (Z) and S2-map (XY)
- Efficient **ER** rejection from **NR** thanks to the Scintillation Pulse Shape Discrimination and S2/S1 Ratio
- **Efficient electron extraction** ($\sim 100\%$) and **large electroluminescence amplification** ($g_2, >20 \text{ PE}/e^-$)



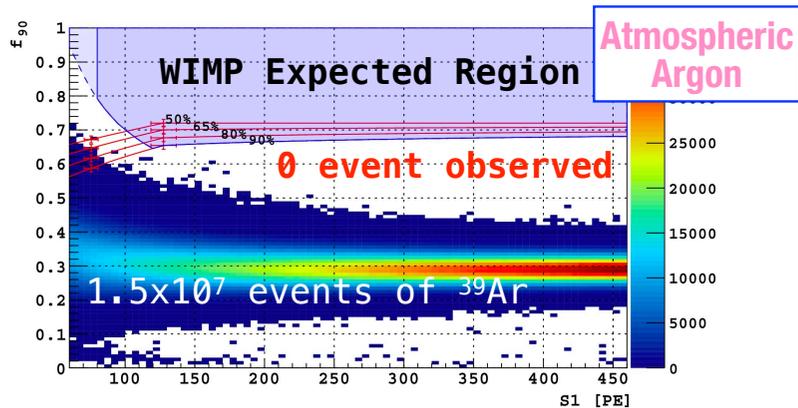
→ Energy Threshold < 100 eV

The DS-50 Results

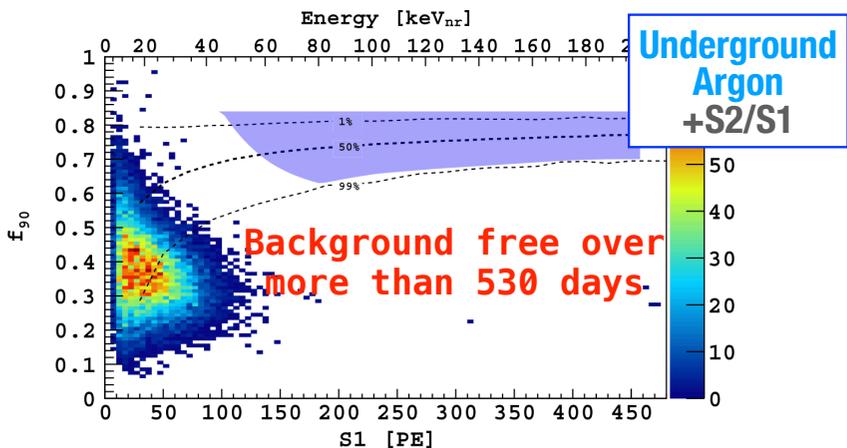
"Heavy" WIMP Search

Pulse Shape Discrimination

PLB 743 (2015) 456-466



PRD 98 (2018) 102006

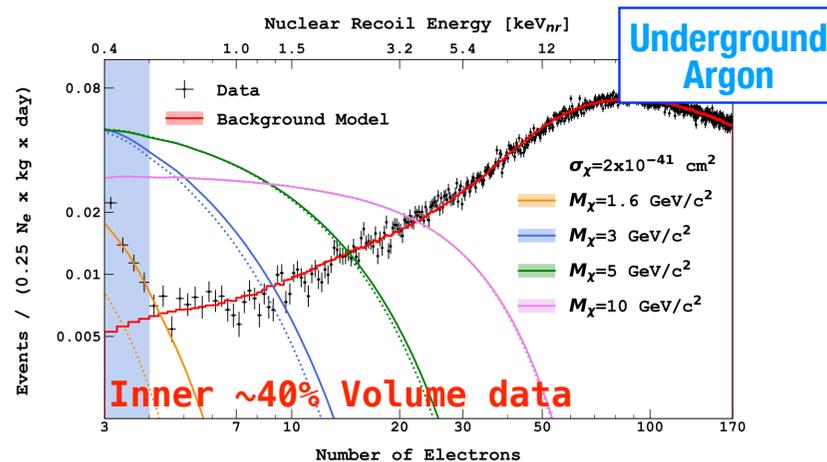


"Light" Dark Matter Search

Ionization Only

PRD 107 (2023) 063001

- No requirement on S1 (- Detection efficiency $g_1 \sim 16\%$)
- No NR/ER discrimination
- $\sim 100\%$ detection efficiency for $3e^-$ (0.04 keV)
- Select single-scatter S2 pulse



Main topic of this talk